Calibration Laboratory of Schmid & Partner **Engineering AG** Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura **Swiss Calibration Service**

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Client

CCS-TW (Auden)

Accreditation No.: SCS 108

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Certificate No: EX3-3665_Mar10

CALIBRATION CERTIFICATE

Object

EX3DV4 - SN:3665

Calibration procedure(s)

QA CAL-01.v6, QA CAL-14.v3, QA CAL-23.v3 and QA CAL-25.v2

Calibration procedure for dosimetric E-field probes

Calibration date:

March 25, 2010

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

ID#	Cal Date (Certificate No.)	Scheduled Calibration
GB41293874	1-Apr-09 (No. 217-01030)	Apr-10
MY41495277	1-Apr-09 (No. 217-01030)	Apr-10
MY41498087	1-Apr-09 (No. 217-01030)	Apr-10
SN: S5054 (3c)	31-Mar-09 (No. 217-01026)	Mar-10
SN: S5086 (20b)	31-Mar-09 (No. 217-01028)	Mar-10
SN: S5129 (30b)	31-Mar-09 (No. 217-01027)	Mar-10
SN: 3013	30-Dec-09 (No. ES3-3013_Dec09)	Dec-10
SN: 660	29-Sep-09 (No. DAE4-660_Sep09)	Sep-10
ID#	Check Date (in house)	Scheduled Check
US3642U01700	4-Aug-99 (in house check Oct-09)	In house check: Oct-11
US37390585	18-Oct-01 (in house check Oct-09)	In house check: Oct10
Name	Function	Signature
	GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 3013 SN: 660 ID # US3642U01700 US37390585	GB41293874 1-Apr-09 (No. 217-01030) MY41495277 1-Apr-09 (No. 217-01030) MY41498087 1-Apr-09 (No. 217-01030) SN: S5054 (3c) 31-Mar-09 (No. 217-01026) SN: S5086 (20b) 31-Mar-09 (No. 217-01028) SN: S5129 (30b) 31-Mar-09 (No. 217-01027) SN: 3013 30-Dec-09 (No. ES3-3013_Dec09) SN: 660 29-Sep-09 (No. DAE4-660_Sep09) ID # Check Date (in house) US3642U01700 4-Aug-99 (in house check Oct-09) US37390585 18-Oct-01 (in house check Oct-09)

Calibrated by:

Katja Pokovic

Technical Manager

Approved by:

Niels Kuster

Quality Manager

Issued: March 25, 2010

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Calibration Laboratory of

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Accreditation No.: SCS 108

Glossary:

TSL NORMx,y,z tissue simulating liquid sensitivity in free space

ConvF DCP sensitivity in TSL / NORMx,y,z diode compression point

CF A, B, C crest factor (1/duty_cycle) of the RF signal modulation dependent linearization parameters

Polarization φ

 ϕ rotation around probe axis

Polarization 9

9 rotation around an axis that is in the plane normal to probe axis (at measurement center),

i.e., 9 = 0 is normal to probe axis

Calibration is Performed According to the Following Standards:

- a) IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- b) IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005

Methods Applied and Interpretation of Parameters:

- NORMx,y,z: Assessed for E-field polarization $\vartheta = 0$ (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide). NORMx,y,z are only intermediate values, i.e., the uncertainties of NORMx,y,z does not effect the E²-field uncertainty inside TSL (see below *ConvF*).
- NORM(f)x,y,z = NORMx,y,z * frequency_response (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of ConvF.
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- Ax,y,z; Bx,y,z; Cx,y,z, VRx,y,z: A, B, C are numerical linearization parameters assessed based on the data of
 power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the
 maximum calibration range expressed in RMS voltage across the diode.
- ConvF and Boundary Effect Parameters: Assessed in flat phantom using E-field (or Temperature Transfer Standard for f ≤ 800 MHz) and inside waveguide using analytical field distributions based on power measurements for f > 800 MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORMx,y,z * ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DASY version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz
- Spherical isotropy (3D deviation from isotropy): in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.

Probe EX3DV4

SN:3665

Manufactured: October 20, 2008
Last calibrated: December 30, 2009
Recalibrated: March 25, 2010

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

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DASY - Parameters of Probe: EX3DV4 SN:3665

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm (μV/(V/m) ²) ^A	0.52	0.58	0.52	± 10.1%
DCP (mV) ^B	94.1	88.0	92.5	

Modulation Calibration Parameters

UID	Communication System Name	PAR		A dB	B dBuV	С	VR mV	Unc ^E (k=2)
10000	cw	0.00	Х	0.00	0.00	1.00	300	± 1.5%
			Υ	0.00	0.00	1.00	300	
			Z	0.00	0.00	1.00	300	

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^A The uncertainties of NormX,Y,Z do not affect the E²-field uncertainty inside TSL (see Pages 5 and 6).

⁸ Numerical linearization parameter: uncertainty not required.

E Uncertainty is determined using the maximum deviation from linear response applying recatangular distribution and is expressed for the square of the field value.

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DASY - Parameters of Probe: EX3DV4 SN:3665

Calibration Parameter Determined in Head Tissue Simulating Media

f [MHz]	Validity [MHz] ^C	Permittivity	Conductivity	ConvF X Co	nvFY (ConvF Z	Alpha	Depth Unc (k=2)
900	± 50 / ± 100	41.5 ± 5%	0.97 ± 5%	9.20	9.20	9.20	0.69	0.65 ± 11.0%
1810	± 50 / ± 100	40.0 ± 5%	1. 40 ± 5 %	7.76	7.76	7.76	0.72	0.60 ± 11.0%
1950	± 50 / ± 100	40.0 ± 5%	1.40 ± 5%	7.43	7.43	7.43	0.59	0.64 ± 11.0%
2300	± 50 / ± 100	39.5 ± 5%	1.67 ± 5%	7.32	7.32	7.32	0.46	0.72 ± 11.0%
2450	± 50 / ± 100	39.2 ± 5%	1.80 ± 5%	7.00	7.00	7.00	0.36	0.85 ± 11.0%

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

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DASY - Parameters of Probe: EX3DV4 SN:3665

Calibration Parameter Determined in Body Tissue Simulating Media

f [MHz]	Validity [MHz] ^C	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
900	± 50 / ± 100	55.0 ± 5%	1. 05 ± 5%	9.18	9.18	9.18	0.76	0.65 ± 11.0%
1810	± 50 / ± 100	53.3 ± 5%	1.52 ± 5%	7.66	7.66	7.66	0.81	0.60 ± 11.0%
1950	± 50 / ± 100	53.3 ± 5%	1.52 ± 5%	7.74	7.74	7.74	0.71	0.65 ± 11.0%
2300	± 50 / ± 100	52.8 ± 5%	1.85 ± 5%	7.50	7.50	7.50	0.48	0.78 ± 11.0%
2450	± 50 / ± 100	52.7 ± 5%	1.95 ± 5%	7.35	7.35	7.35	0.68	0.65 ± 11.0%
2600	± 50 / ± 100	52.5 ± 5%	2.16 ± 5%	7.2 7	7.27	7.27	0.37	0.90 ± 11.0%
3500	± 50 / ± 100	51.3 ± 5%	3.31 ± 5%	6.08	6.08	6.08	0.25	1.69 ± 13.1%
4950	± 50 / ± 100	49.4 ± 5%	5.01 ± 5%	4.22	4.22	4.22	0.50	1.95 ± 13.1%
5200	± 50 / ± 100	49.0 ± 5%	5.30 ± 5%	4.14	4.14	4.14	0.55	1.95 ± 13.1%
5300	± 50 / ± 100	48.5 ± 5%	5.42 ± 5%	4.03	4.03	4.03	0.55	1.96 ± 13.1%
5500	± 50 / ± 100	48.6 ± 5%	5.65 ± 5%	3.76	3.76	3.76	0.58	1.95 ± 13.1%
5600	± 50 / ± 100	48.5 ± 5%	5.77 ± 5%	3.39	3.39	3.39	0.65	1.95 ± 13.1%
5800	± 50 / ± 100	48.2 ± 5%	6.00 ± 5%	3.92	3.92	3.92	0.65	1.95 ± 13.1%

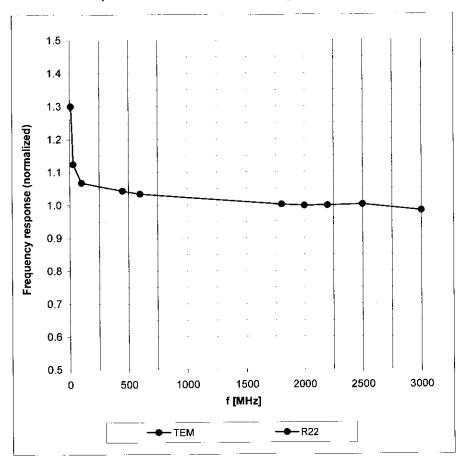
^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

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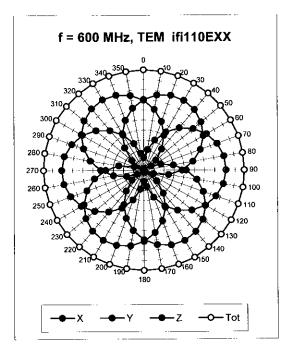
Frequency Response of E-Field

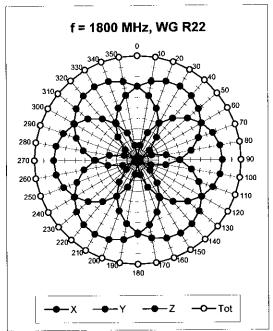
(TEM-Cell:ifi110 EXX, Waveguide: R22)

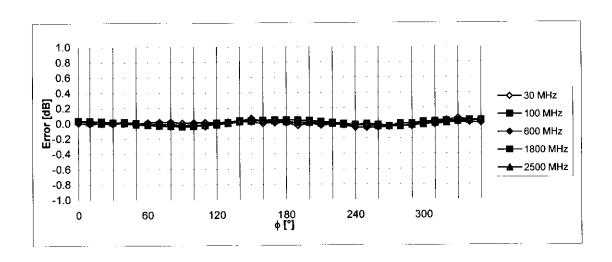


Uncertainty of Frequency Response of E-field: ± 6.3% (k=2)

Receiving Pattern (ϕ), $\vartheta = 0^{\circ}$



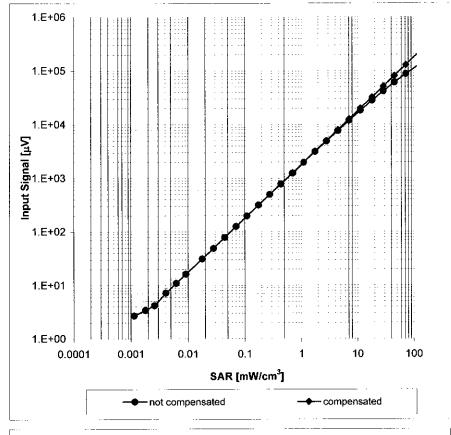


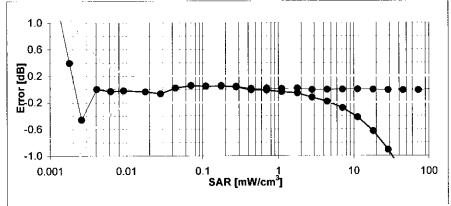


Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

Dynamic Range f(SAR_{head})

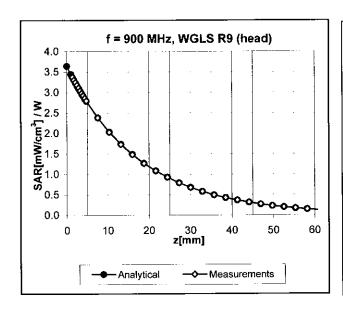
(Waveguide R22, f = 1800 MHz)

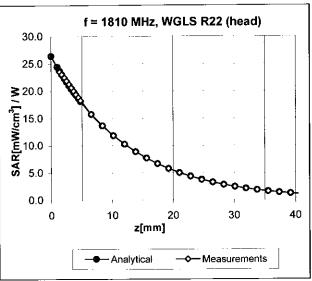




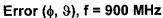
Uncertainty of Linearity Assessment: ± 0.6% (k=2)

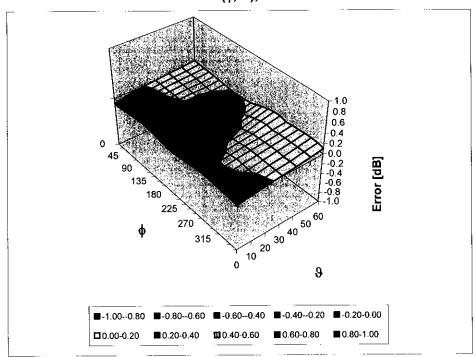
Conversion Factor Assessment





Deviation from Isotropy in HSL





Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

Other Probe Parameters

Sensor Arrangement	Triangular
Connector Angle (°)	Not applicable
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	10 mm
Tip Length	9 mm
Tip Diameter	2.5 mm
Probe Tip to Sensor X Calibration Point	1 mm
Probe Tip to Sensor Y Calibration Point	1 mm
Probe Tip to Sensor Z Calibration Point	1 mm
Recommended Measurement Distance from Surface	2 mm

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